

Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

Characteristic			Symbol	Q1 Value	Q2 Value	Unit	
Drain-Source Voltage			V _{DSS}	30	-30	V	
Gate-Source Voltage			V _{GSS}	±20	±20	V	
Continuous Drain Current (Note 6) V _{GS} = 10V	Steady State	T _A = +25°C	I _D	4.6	-3.3	A	
		T _A = +70°C		3.6	-2.6		
Maximum Continuous Body Diode Forward Current (Note 6)			I _S	1.5	-1.3	A	
Pulsed Drain Current (380μs Pulse, Duty Cycle = 1%)			I _{DM}	20	-10	A	

Thermal Characteristics

Characteristic		Symbol	Value	Unit
Total Power Dissipation (Note 5)	T _A = +25°C	P _D	0.7	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	R _{θJA}	186	°C/W
Total Power Dissipation (Note 6)	T _A = +25°C	P _D	1.1	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	R _{θJA}	117	°C/W
Thermal Resistance, Junction to Case		R _{θJC}	45	
Operating and Storage Temperature Range		T _J , T _{STG}	-55 to +150	°C

Electrical Characteristics Q1 N-CHANNEL (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV _{DSS}	30	—	—	V	V _{GS} = 0V, I _D = 250µA
Zero Gate Voltage Drain Current	I _{DSS}	—	—	1.0	µA	V _{DS} = 30V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±20V, V _{DS} = 0V
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	V _{GS(TH)}	1.0	—	2.5	V	V _{DS} = V _{GS} , I _D = 250µA
Static Drain-Source On-Resistance	R _{DS(ON)}	—	34	50	mΩ	V _{GS} = 10V, I _D = 3.5A
			44	90		V _{GS} = 4.5V, I _D = 2.0A
Diode Forward Voltage	V _{SD}	—	0.8	1.0	V	V _{GS} = 0V, I _S = 1A
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C _{iss}	—	190	—	pF	V _{DS} = 15V, V _{GS} = 0V f = 1.0MHz
Output Capacitance	C _{oss}	—	36	—		
Reverse Transfer Capacitance	C _{rss}	—	26	—		
Gate Resistance	R _g	—	4.2	—	Ω	V _{DS} = 0V, V _{GS} = 0V, f = 1MHz
Total Gate Charge (V _{GS} = 4.5V)	Q _g	—	2.1	—	nC	V _{DS} = 15V, I _D = 4A
Total Gate Charge (V _{GS} = 10V)	Q _g	—	4.5	—		
Gate-Source Charge	Q _{gs}	—	0.5	—		
Gate-Drain Charge	Q _{gd}	—	0.8	—		
Turn-On Delay Time	t _{D(ON)}	—	1.7	—	ns	V _{DS} = 15V, V _{GS} = 10V, R _G = 3Ω, I _D = 4A
Turn-On Rise Time	t _R	—	5.7	—		
Turn-Off Delay Time	t _{D(OFF)}	—	6.0	—		
Turn-Off Fall Time	t _F	—	1.6	—		
Reverse Recovery Time	t _{RR}	—	4.2	—	ns	I _F = 4A, di/dt = 100A/µs
Reverse Recovery Charge	Q _{RR}	—	0.5	—	nC	

- Notes:
5. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.
 6. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
 7. Short duration pulse test used to minimize self-heating effect.
 8. Guaranteed by design. Not subject to production testing.

Electrical Characteristics Q2 P-CHANNEL (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV _{DSS}	-30	—	—	V	V _{GS} = 0V, I _D = -250μA
Zero Gate Voltage Drain Current	I _{DSS}	—	—	-1.0	μA	V _{DS} = -30V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±20V, V _{DS} = 0V
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	V _{GS(TH)}	-1	—	-2.5	V	V _{DS} = V _{GS} , I _D = -250μA
Static Drain-Source On-Resistance	R _{DS(ON)}	—	83 128	95 140	mΩ	V _{GS} = -10V, I _D = -3.8A V _{GS} = -4.5V, I _D = -3.0A
Diode Forward Voltage	V _{SD}	—	-0.8	-1.2	V	V _{GS} = 0V, I _S = -1A
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C _{iss}	—	254	—	pF	V _{DS} = -15V, V _{GS} = 0V, f = 1.0MHz
Output Capacitance	C _{oss}	—	14	—		
Reverse Transfer Capacitance	C _{rss}	—	7	—		
Gate Resistance	R _g	—	54	—	Ω	V _{DS} = 0V, V _{GS} = 0V, f = 1MHz
Total Gate Charge (V _{GS} = -4.5V)	Q _g	—	3.1	—	nC	V _{DS} = -15V, I _D = -3.8A
Total Gate Charge (V _{GS} = -10V)	Q _g	—	6.5	—		
Gate-Source Charge	Q _{gs}	—	0.8	—		
Gate-Drain Charge	Q _{gd}	—	1.4	—		
Turn-On Delay Time	t _{D(ON)}	—	3.5	—	ns	V _{GS} = -10V, V _{DS} = -15V, R _G = 6Ω, R _L = 15Ω
Turn-On Rise Time	t _R	—	6.2	—		
Turn-Off Delay Time	t _{D(OFF)}	—	21.8	—		
Turn-Off Fall Time	t _F	—	13.1	—		
Reverse Recovery Time	t _{RR}	—	9.6	—	ns	I _F = -1.0A, di/dt = -100A/μs
Reverse Recovery Charge	Q _{RR}	—	2.4	—	nC	I _F = -1.0A, di/dt = -100A/μs

Notes: 7. Short duration pulse test used to minimize self-heating effect.
8. Guaranteed by design. Not subject to production testing.

Typical Characteristics - N-CHANNEL

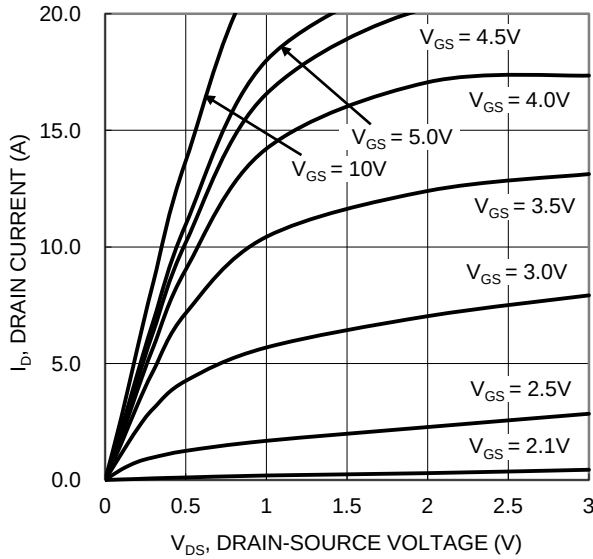


Figure 1. Typical Output Characteristic

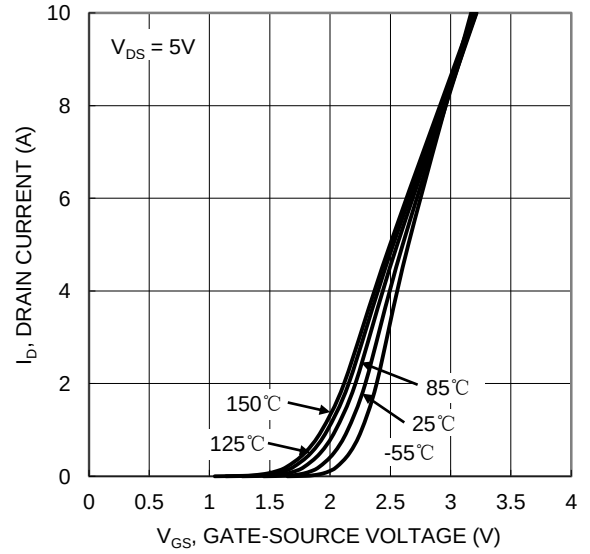


Figure 2. Typical Transfer Characteristic

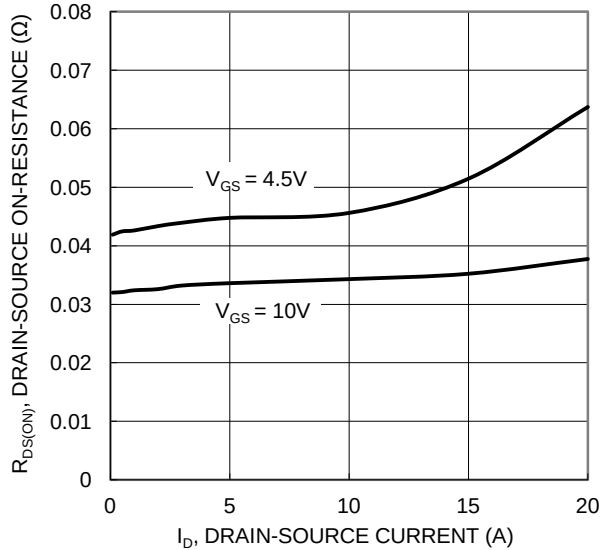


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

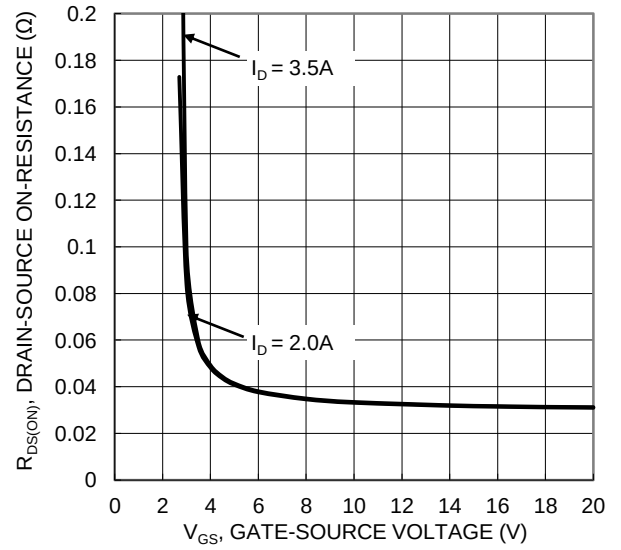


Figure 4. Typical Transfer Characteristic

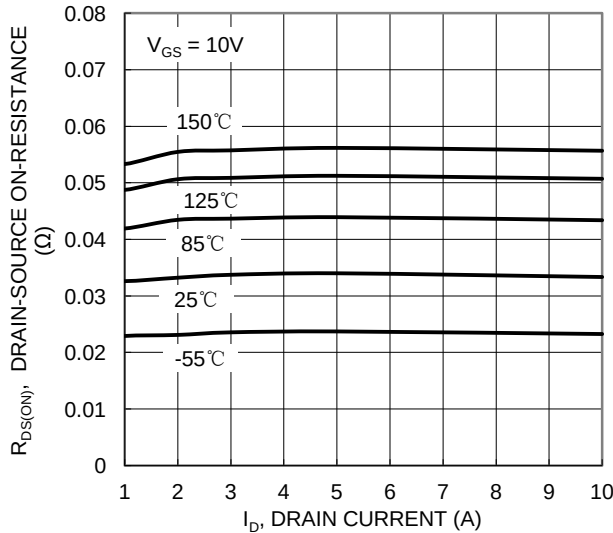


Figure 5. Typical On-Resistance vs. Drain Current and Junction Temperature

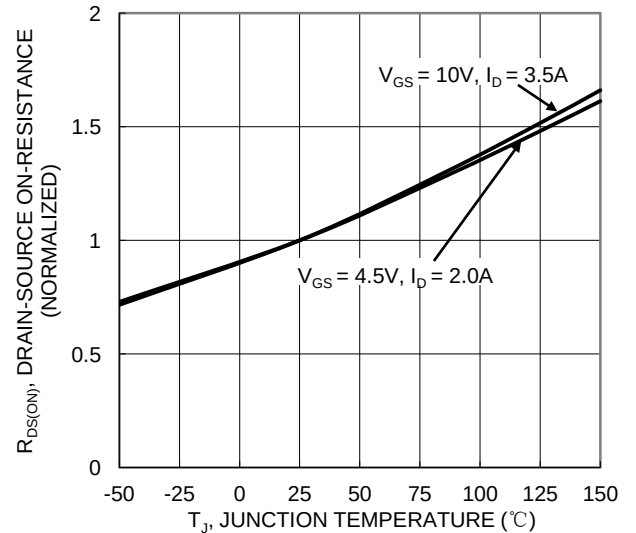


Figure 6. On-Resistance Variation with Junction Temperature

Typical Characteristics - N-CHANNEL (Cont.)

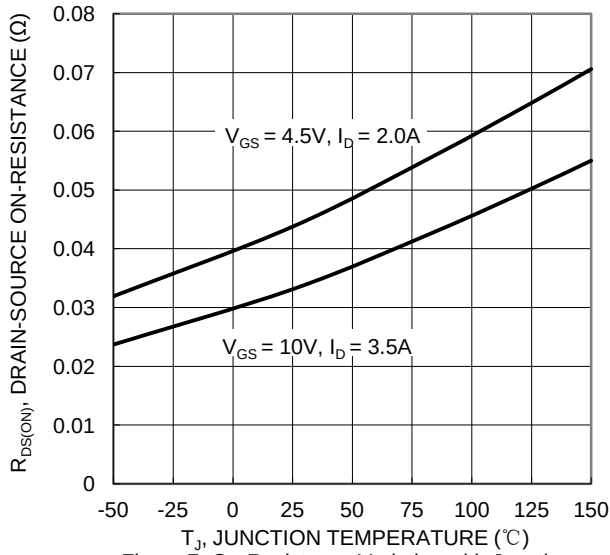


Figure 7. On-Resistance Variation with Junction Temperature

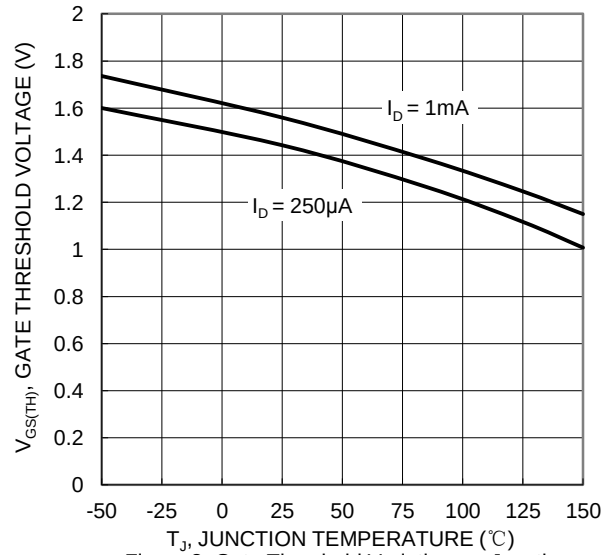


Figure 8. Gate Threshold Variation vs. Junction Temperature

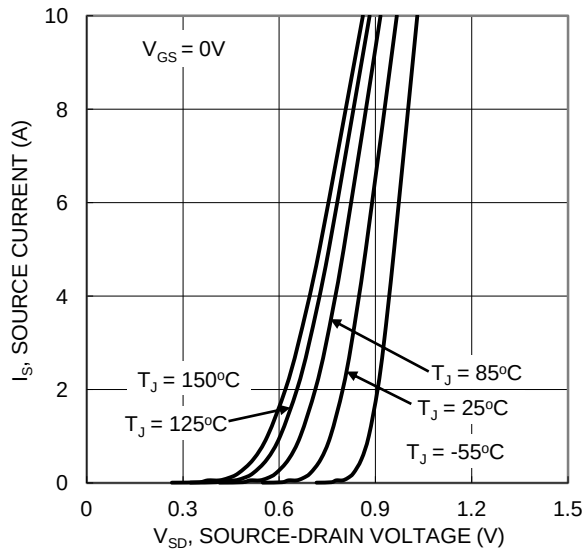


Figure 9. Diode Forward Voltage vs. Current

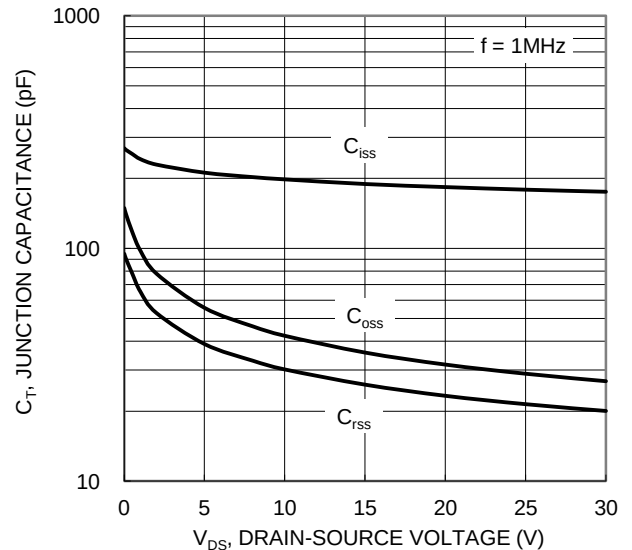


Figure 10. Typical Junction Capacitance

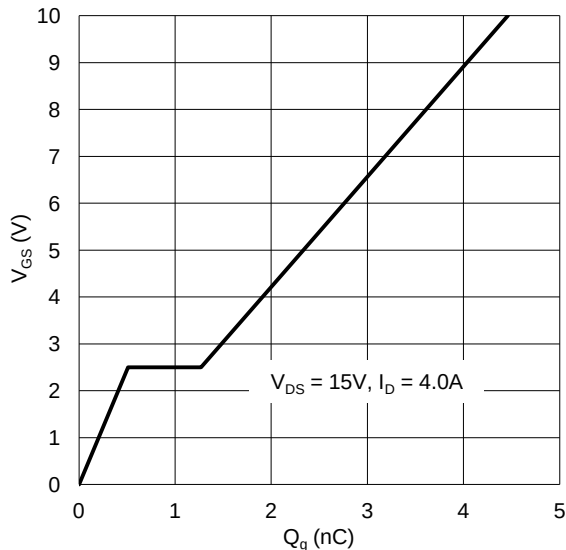


Figure 11. Gate Charge

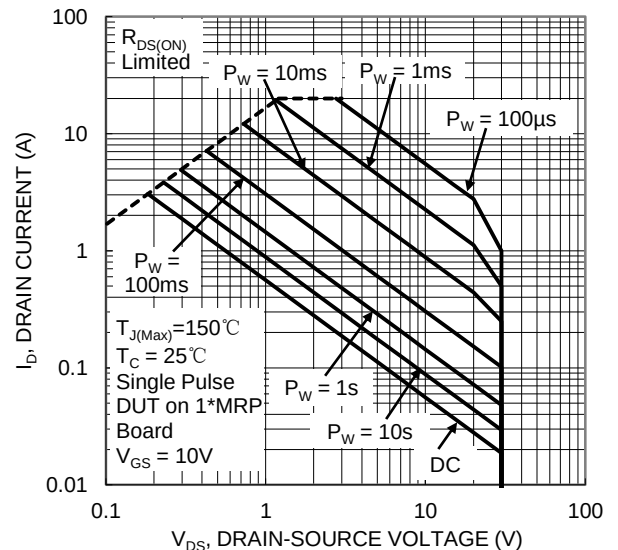


Figure 12. SOA, Safe Operation Area

Typical Characteristics - P-CHANNEL

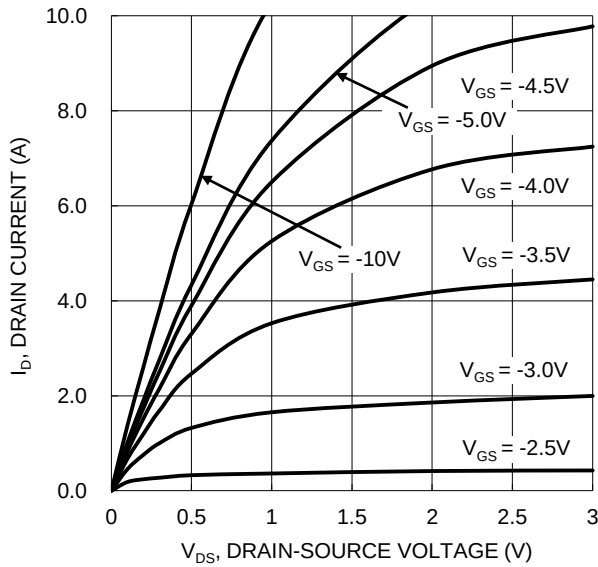


Figure 13. Typical Output Characteristic

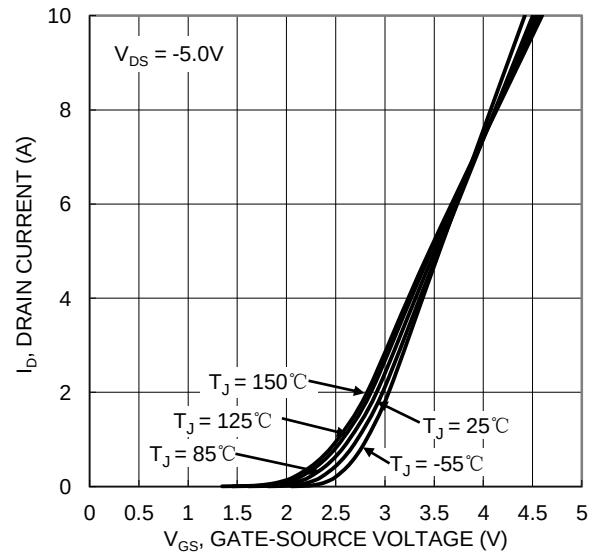


Figure 14. Typical Transfer Characteristic

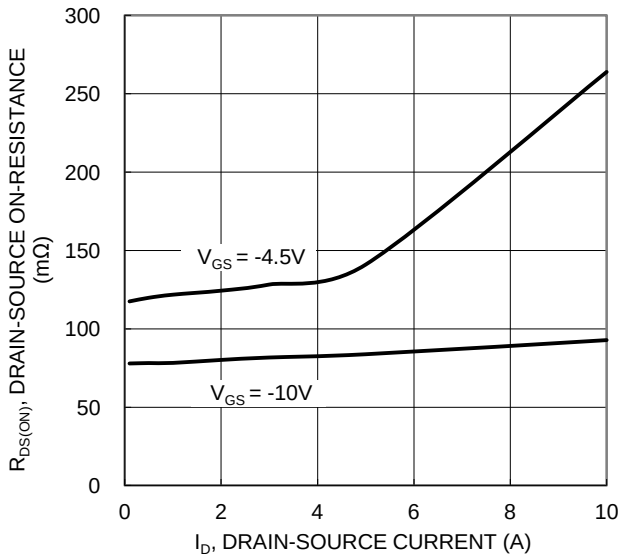


Figure 15. Typical On-Resistance vs. Drain Current and Gate Voltage

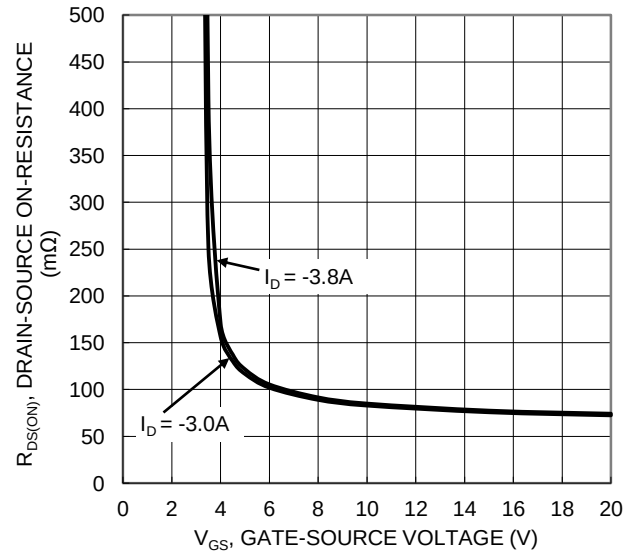


Figure 16. Typical Transfer Characteristic

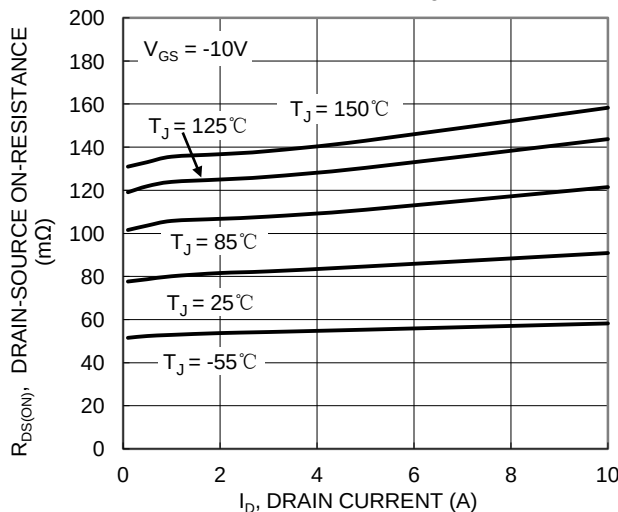


Figure 17. Typical On-Resistance vs. Drain Current and Temperature

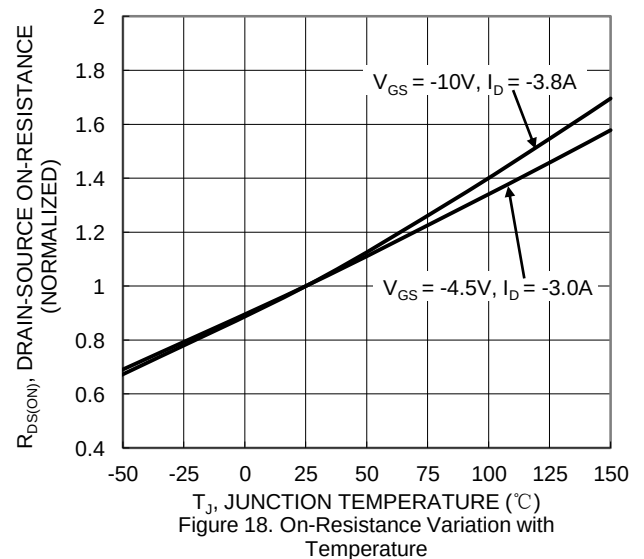


Figure 18. On-Resistance Variation with Temperature

Typical Characteristics - P-CHANNEL (Cont.)

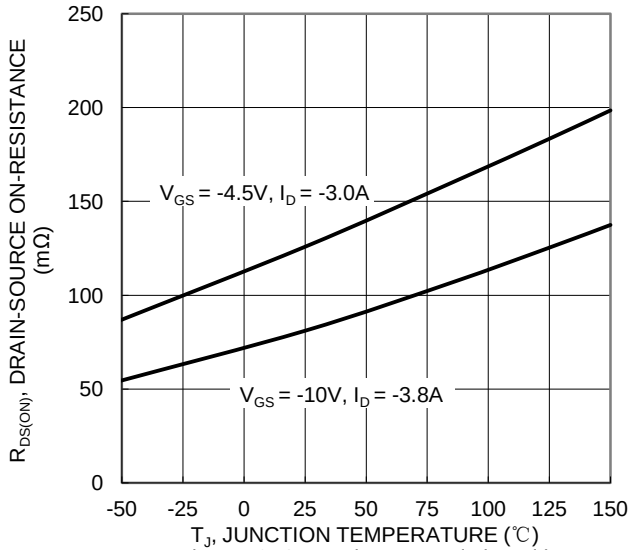


Figure 19. On-Resistance Variation with Temperature

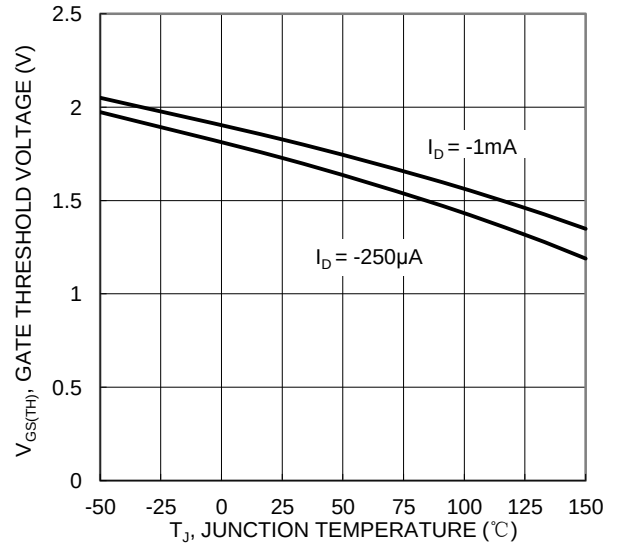


Figure 20. Gate Threshold Variation vs. Junction Temperature

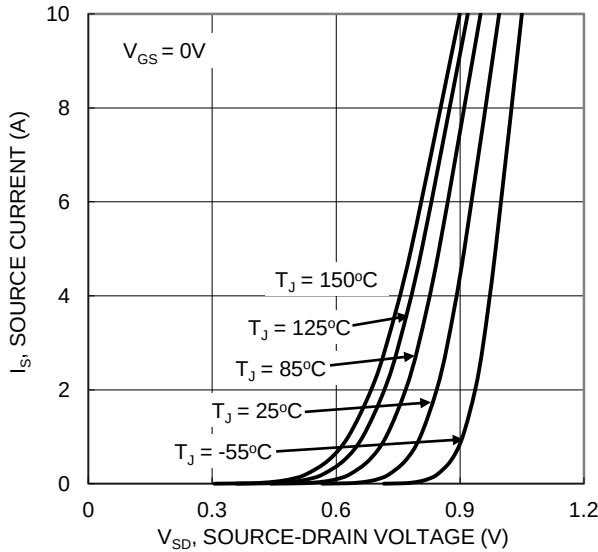


Figure 21. Diode Forward Voltage vs. Current

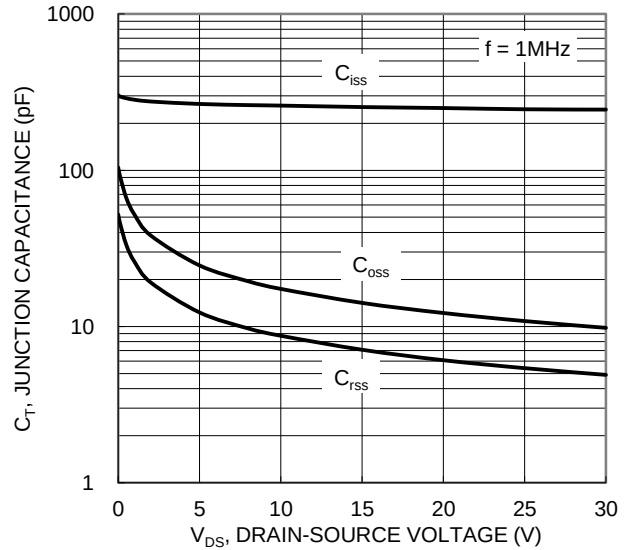


Figure 22. Typical Junction Capacitance

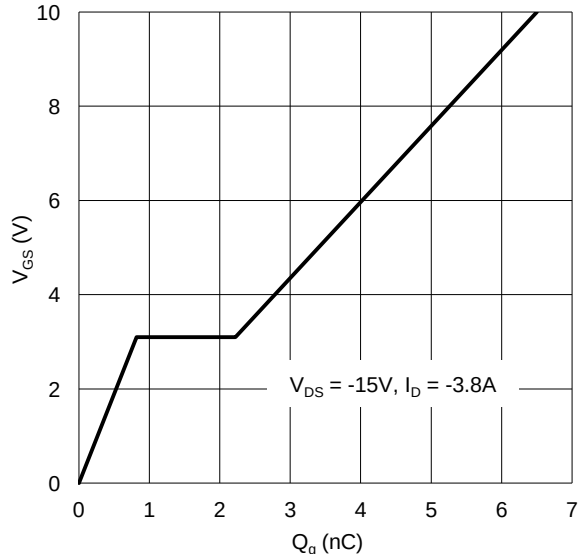


Figure 23. Gate Charge

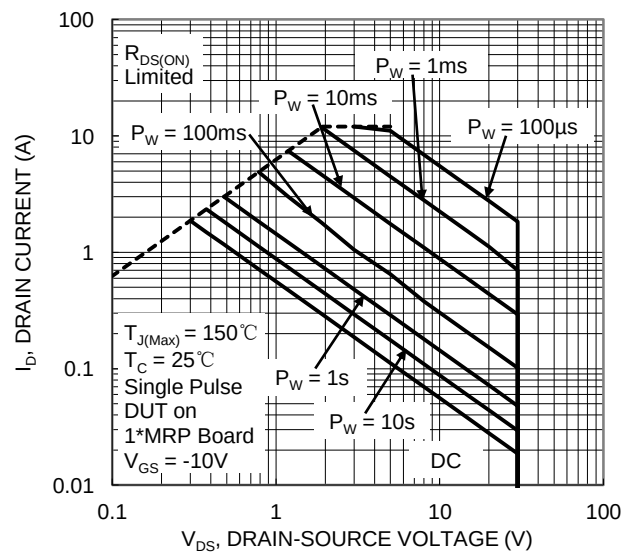
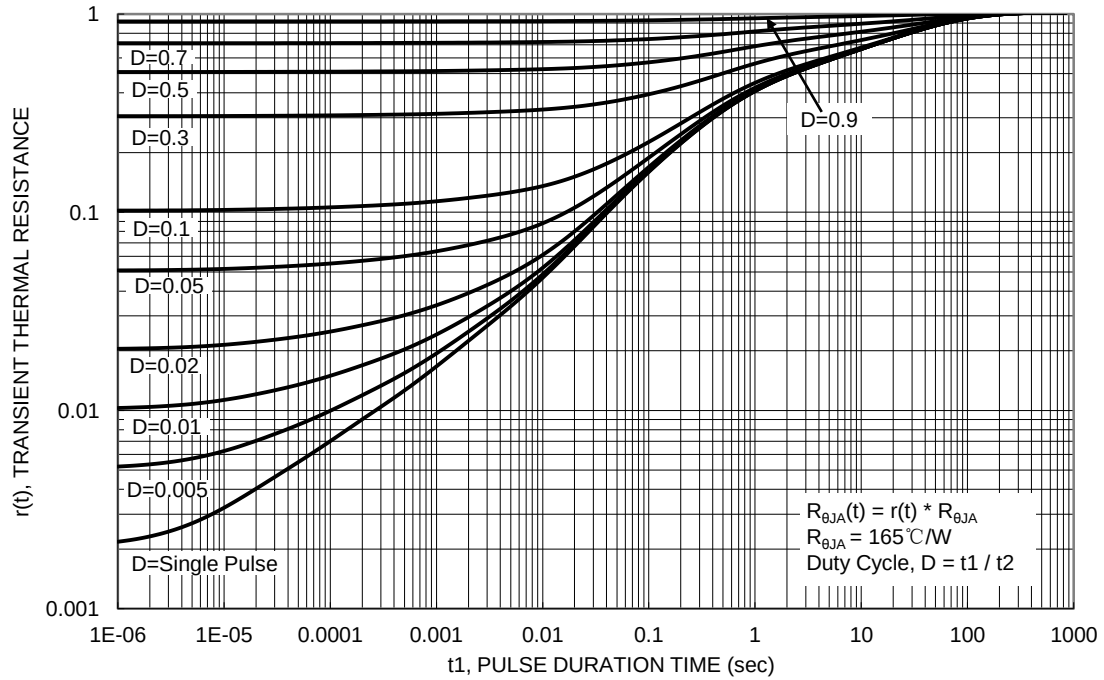


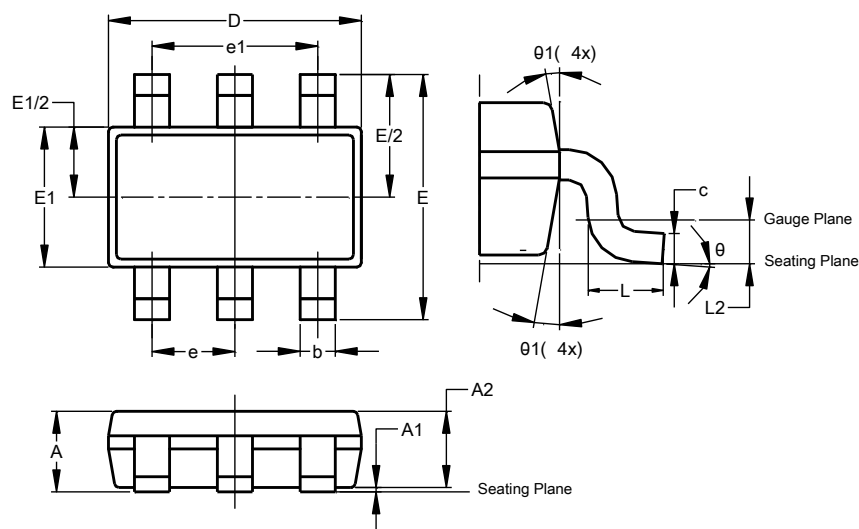
Figure 24. SOA, Safe Operation Area



Package Outline Dimensions

Please see <http://www.diodes.com/package-outlines.html> for the latest version.

TSOT26

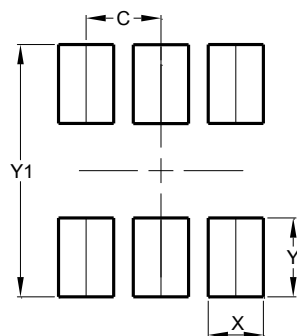


TSOT26			
Dim	Min	Max	Typ
A	–	1.00	–
A1	0.010	0.100	–
A2	0.840	0.900	–
D	2.800	3.000	2.900
E	2.800 BSC		
E1	1.500	1.700	1.600
b	0.300	0.450	–
c	0.120	0.200	–
e	0.950 BSC		
e1	1.900 BSC		
L	0.30	0.50	–
L2	0.250 BSC		
θ	0°	8°	4°
θ1	4°	12°	–
All Dimensions in mm			

Suggested Pad Layout

Please see <http://www.diodes.com/package-outlines.html> for the latest version.

TSOT26



Dimensions	Value (in mm)
C	0.950
X	0.700
Y	1.000
Y1	3.199

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